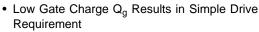


## U5N60HA-VB Datasheet

# N-Channel 650V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	65	0		
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	0.95		
Q <sub>g</sub> (Max.) (nC)	15	5		
Q <sub>gs</sub> (nC)	3			
Q <sub>gd</sub> (nC)	6			
Configuration	Sing	Single		

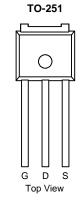
### **FEATURES**

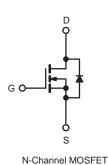




• Improved Gate, Avalanche and Dynamic dV/dt Ruggedness

- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





**ABSOLUTE MAXIMUM RATINGS** T<sub>C</sub> = 25 °C, unless otherwise noted **PARAMETER** SYMBOL LIMIT UNIT

Drain-Source Voltage		$V_{DS}$	650	V
Gate-Source Voltage	$V_{GS}$	± 30	V	
Continuous Drain Current <sup>e</sup>	$V_{GS}$ at 10 V $T_C = 25 ^{\circ}C$		5	A
Continuous Drain Current	$V_{GS}$ at 10 V $T_C = 100 ^{\circ}C$	I <sub>D</sub>	4	
Pulsed Drain Current <sup>a</sup>		I <sub>DM</sub>	16	
Linear Derating Factor			1.67/0.8/0.3	W/°C
Single Pulse Avalanche Energy <sup>b</sup>		E <sub>AS</sub>	120	mJ
Repetitive Avalanche Current <sup>a</sup>		I <sub>AR</sub>	34	Α
Repetitive Avalanche Energy <sup>a</sup>		E <sub>AR</sub>	17	mJ
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	205/35/30	W
Peak Diode Recovery dV/dtc	ak Diode Recovery dV/dt <sup>c</sup>		4.5	V/ns
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)d	for 10 s		300	
Mounting Torque	C 22 - 1 M2 - 2 - 2 - 2 - 2 - 2 - 2 - 2 - 2 - 2		10	lbf ⋅ in
Mounting Torque	6-32 or M3 screw		1.1	N⋅m

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T $_J$  = 25 °C, L = 24 mH, R $_G$  = 25  $\Omega$ , I $_{AS}$  = 3.2 A (see fig. 12). c. I $_{SD}$  ≤ 3.2 A, dl/dt ≤ 90 A/ $\mu$ s, V $_{DD}$  ≤ V $_{DS}$ , T $_J$  ≤ 150 °C.

- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	3.6/1.2/0.6	C/VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	Reference to 25 °C, I <sub>D</sub> = 1 mA <sup>d</sup>		0.6	-	mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		-	4.0	V
Gate-Source Leakage	$I_{GSS}$	,	V <sub>GS</sub> = ± 30 V		-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V V <sub>DS</sub> = 520 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	10 100	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 2.5 A <sup>b</sup>	-	0.95	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	= 50 V, I <sub>D</sub> = 2.5 A	8	-	-	S
Dynamic		1				l.	<u> </u>
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 V$ ,		320	-	
Output Capacitance	C <sub>oss</sub>		$V_{DS} = 25 \text{ V},$	-	75	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5		-	4	-	
Output Capacitance	C <sub>oss</sub>		V <sub>DS</sub> = 1.0 V, f = 1.0 MHz	-	500	-	pF -
		V <sub>GS</sub> = 0 V	V <sub>DS</sub> = 520 V, f = 1.0 MHz	-	83	-	
Effective Output Capacitance	Coss eff.		V <sub>DS</sub> = 0 V to 520 V <sup>c</sup>		14	-	
Total Gate Charge	$Q_g$				-	15	nC
Gate-Source Charge	$Q_{gs}$	V <sub>GS</sub> = 10 V	$I_D = 2.5 \text{ A}, V_{DS} = 400 \text{ V}$	-	-	3	
Gate-Drain Charge	$Q_{gd}$		see fig. 6 and 13 <sup>b</sup>		-	6	1
Turn-On Delay Time	t <sub>d(on)</sub>			-	18	-	ns
Rise Time	t <sub>r</sub>		$V_{DD} = 325 \text{ V}, I_D = 3.2 \text{ A}$		40	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_G = 9.1 \Omega, R_D = 62 \Omega,$ see fig. $10^b$		-	50	-	
Fall Time	t <sub>f</sub>			-	30	-	
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5	- A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	16	
Body Diode Voltage	$V_{SD}$	$T_J = 25  ^{\circ}\text{C},  I_S = 3.2  \text{A},  V_{GS} = 0  \text{V}^{\text{b}}$		-	-	1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 3.2 A, dl/dt = 100 A/μs <sup>b</sup>		-	180	-	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	2.1	3.2	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	ırn-on time is negligible (turn	on is don	ninated by	y L <sub>S</sub> and	L <sub>D</sub> )

#### **Notes**

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.
- c.  $C_{oss}$  eff. is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DS}$ .
- d. t = 60 s, f = 60 Hz.



### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

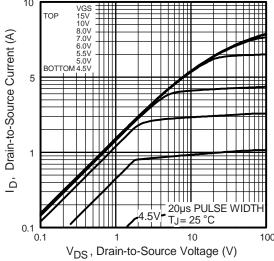


Fig. 1 - Typical Output Characteristics

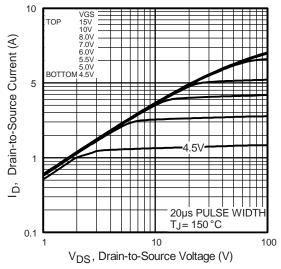


Fig. 2 - Typical Output Characteristics

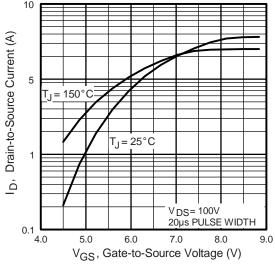


Fig. 3 - Typical Transfer Characteristics

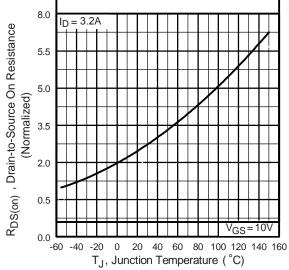


Fig. 4 - Normalized On-Resistance vs. Temperature



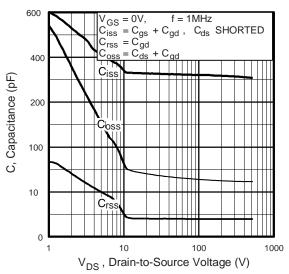


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

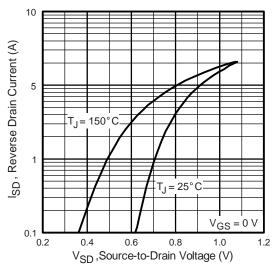


Fig. 7 - Typical Source-Drain Diode Forward Voltage

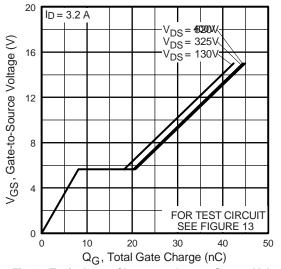


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

4

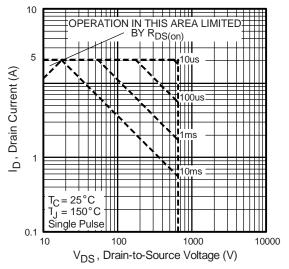


Fig. 8 - Maximum Safe Operating Area



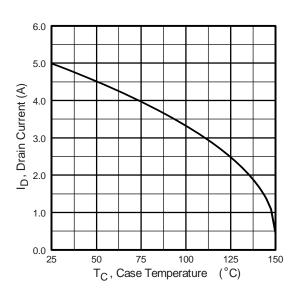


Fig. 9 - Maximum Drain Current vs. Case Temperature

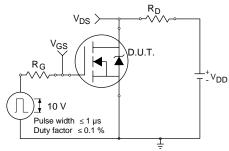


Fig. 10a - Switching Time Test Circuit

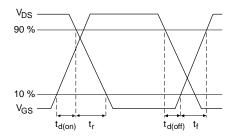


Fig. 10b - Switching Time Waveforms

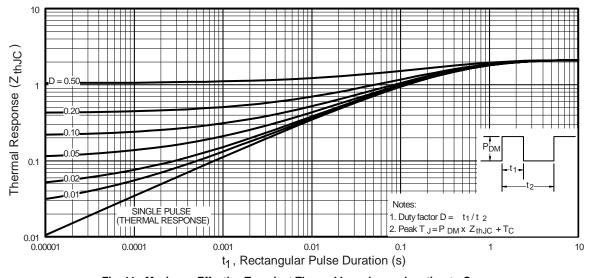


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

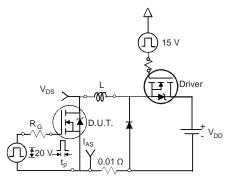


Fig. 12a - Unclamped Inductive Test Circuit

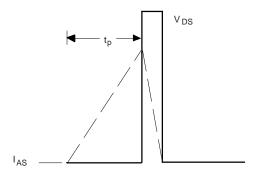


Fig. 12b - Unclamped Inductive Waveforms



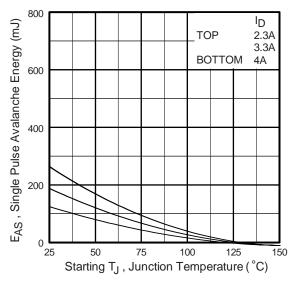


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

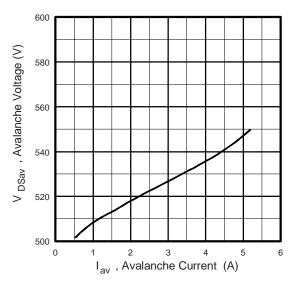


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

6

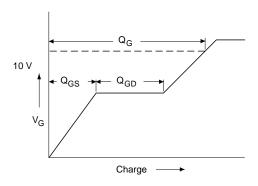


Fig. 13a - Basic Gate Charge Waveform

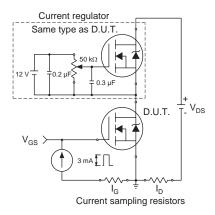
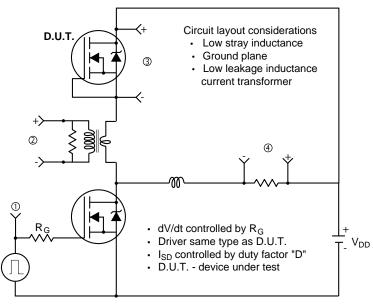


Fig. 13b - Gate Charge Test Circuit



7

## Peak Diode Recovery dV/dt Test Circuit



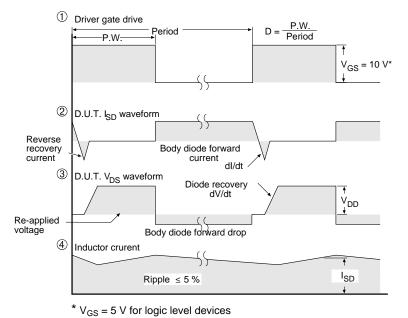
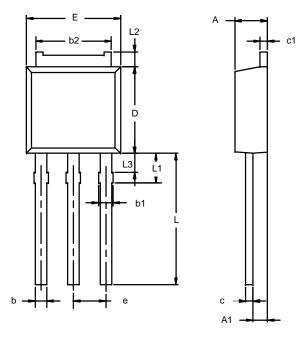


Fig. 14 - For N-Channel



## TO-251AA (DPAK)



Note: Dimension L3 is for reference only.

	MILLIM	IETERS	INCHES		
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Ε	6.48	6.73	0.255	0.265	
е	2.28 BSC		0.090 BSC		
L	8.89	9.53	0.350	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					



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